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Complete if Known

Application Number	09/824,751
Confirmation Number	9722
Filing Date	April 04, 2001
First Named Inventor	Hiroki KOIKE
Art Unit	2818
Examiner Name	Esaw T. Abraham
Attorney Docket Number	Q63945

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U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code ² (if known)		
		US			
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FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation ⁶
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NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation ⁶
EA		Byung-Gil Jeon et al., "A novel cell charge evaluation scheme and rest method for 4 Mb nonvolatile ferroelectric RAM" ICVC '99. 6th INTERNATIONAL CONFERENCE ON VLSI AND CAD (CAT. NO. 99EX361), ICVC '99 6TH INTERNATIONAL CONFERENCE IN VLSI AND CAD, SEOUL, SOUTH KOREA, 26-27 OCT. 1999, pages 281-284, XP002271012 1999, Piscataway, NJ, USA IEEE, USA ASBN: 0-7803-5727-2.	
EA		Byung-Gil Jeon et al.: "A 0.4 μ m, 3.3 V 1T1C 4 Mb nonvolatile ferroelectric RAM with fixed bit-line reference voltage scheme and data protection circuit", 2000 IEEE INTERNATIONAL SOLID-STATE CIRCUITS CONFERENCE. DIGEST OF TECHNICAL PAPERS (CAT. NO. 00CH37056), 2000 IEEE INTERNATIONAL SOLID-STATE CIRCUITS CONFERENCE. DIGEST OF TECHNICAL PAPERS, SAN FRANCISCO, CA, USA, IEEE, USA ISBN: 0-7803-5853-8	

Examiner Signature

Esaw Abraham

Date Considered

03/03/05

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